AMENDMENTS TO THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the application:

LISTING OF CLAIMS:

- 1.-11. (canceled).
- 12. (currently amended) A system for manufacturing a fullerene derivative, comprising:

means for generating high electron temperature plasma whose configured to maintain an electron energy is kept at 15 to 50 eV in order to generate a positive monovalent ion M⁺ from a gas containing an atom M which acts acting as a moiety in the production of a fullerene derivative;

fullerene introducing means for introducing a fullerene into plasma comprised of $\mathbf{M}^{\scriptscriptstyle +}$ and electrons to produce a fullerene ion; and

a deposition substrate where whereon a fullerene derivative produced as a result of \underline{a} reaction between the fullerene ion and M^+ is allowed to deposit is deposited.

13. (currently amended) A system for manufacturing a fullerene derivative, comprising:

means for generating high electron temperature plasma $\frac{1}{2}$ whose configured to maintain an electron energy $\frac{1}{2}$ kept at 15 to 50 eV $\frac{1}{2}$ order to generate a positive monovalent ion $\frac{1}{2}$ from a

gas containing an atom M $\frac{\text{which acts}}{\text{acting}}$ as a moiety in the production of a fullerene derivative;

fullerene introducing means for introducing a fullerene; and

a deposition substrate,

wherein plasma comprised of M^+ is driven against the deposition substrate while at the same time fullerene ejected via the fullerene introducing means is allowed to impinge onto the deposition substrate so that M^+ and fullerene react with each other to produce a fullerene derivative which deposits on the deposition substrate.

- 14. (previously presented) The system as described in Claim 12 for manufacturing a fullerene derivative wherein the high electron temperature plasma generating means comprises at least a pair of coils for generating a mirror field which prohibits the dispersion of positive ions produced.
- 15. (previously presented) The system as described in Claim 13 for manufacturing a fullerene derivative wherein the high electron temperature plasma generating means comprises at least a pair of coils for generating a mirror field which prohibits the dispersion of positive ions produced.

Docket No. 8075-1097 Appln. No. 10/581,441

- 16. (previously presented) The system as described in Claim 12 for manufacturing a fullerene derivative wherein the high electron temperature plasma generating means comprises at least a pair of coils for generating a mirror field which prohibits the dispersion of positive ions produced, and a four phased helical antenna located between the pair of coils.
- 17. (previously presented) The system as described in Claim 13 for manufacturing a fullerene derivative wherein the high electron temperature plasma generating means comprises at least a pair of coils for generating a mirror field which prohibits the dispersion of positive ions produced, and a four phased helical antenna located between the pair of coils.
- 18. (previously presented) The system as described in Claim 12 for manufacturing a fullerene derivative wherein the high electron temperature plasma generating means comprises gas introducing means, a microwave generator for exciting gas to produce positive ions therefrom, a pair of coils for generating a mirror field which prohibits dispersion of the positive ions produced, and a four phased helical antenna located between the pair of coils.
- 19. (previously presented) The system as described in Claim 13 for manufacturing a fullerene derivative wherein the

high electron temperature plasma generating means comprises gas introducing means, a microwave generator for exciting gas to produce positive ions therefrom, a pair of coils for generating a mirror field which prohibits dispersion of the positive ions produced, and a four phased helical antenna located between the pair of coils.

20. (currently amended) The system as described in claim 12 for manufacturing a fullerene derivative, further comprising:

electron energy control means for controlling the energy of electrons in a plasma to be in the \underline{a} range of 1 to 10 eV, the electron energy control means being located downstream of the high electron temperature plasma generating means in terms of the flow of plasma.

- 21. (previously presented) The system as described in Claim 20 for manufacturing a fullerene derivative wherein the electron energy control means controls the energy of electrons by applying a control voltage to an electrode located upstream of the fullerene introducing means in terms of the flow of plasma.
- 22. (previously presented) The system as described in Claim 12 for manufacturing a fullerene derivative.